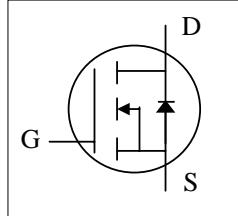




- ▼ Simple Drive Requirement
- ▼ Low Gate Charge
- ▼ Fast Switching Characteristic
- ▼ Halogen Free & RoHS Compliant Product

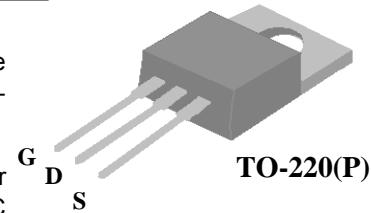


BV_{DSS}	40V
$R_{DS(ON)}$	4mΩ
I_D	160A

Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is widely preferred for commercial-industrial power applications and suited for low voltage applications such as DC/DC converters.



TO-220(P)

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	40	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current (Chip)	160	A
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^3$	80	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^3$	80	A
I_{DM}	Pulsed Drain Current ¹	300	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation	187	W
T_{STG}	Storage Temperature Range	-55 to 175	°C
T_J	Operating Junction Temperature Range	-55 to 175	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Maximum Thermal Resistance, Junction-case	0.8	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient	62	°C/W



Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	40	-	-	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=40\text{A}$	-	-	4	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=30\text{A}$	-	-	5	$\text{m}\Omega$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$\text{V}_{\text{DS}}=10\text{V}, \text{I}_D=30\text{A}$	-	80	-	S
I_{DSS}	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=40\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	25	μA
I_{GSS}	Gate-Source Leakage	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_{g}	Total Gate Charge	$\text{I}_D=30\text{A}$	-	25	40	nC
Q_{gs}	Gate-Source Charge	$\text{V}_{\text{DS}}=32\text{V}$	-	6.5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$\text{V}_{\text{GS}}=4.5\text{V}$	-	14	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$\text{V}_{\text{DS}}=20\text{V}$	-	11	-	ns
t_r	Rise Time	$\text{I}_D=30\text{A}$	-	62	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$\text{R}_G=2.4\Omega$	-	30	-	ns
t_f	Fall Time	$\text{V}_{\text{GS}}=10\text{V}$	-	9	-	ns
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}$	-	2800	4500	pF
C_{oss}	Output Capacitance	$\text{V}_{\text{DS}}=25\text{V}$	-	590	-	pF
C_{rss}	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	165	-	pF
R_{g}	Gate Resistance	$f=1.0\text{MHz}$	-	1.6	2.4	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$\text{I}_S=40\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1.2	V
t_{rr}	Reverse Recovery Time	$\text{I}_S=10\text{A}, \text{V}_{\text{GS}}=0\text{V},$ $d\text{I}/dt=100\text{A}/\mu\text{s}$	-	41	-	ns
			-	47	-	nC

Notes:

1. Pulse width limited by Max. junction temperature.
2. Pulse test
3. Package limitation current is 80A.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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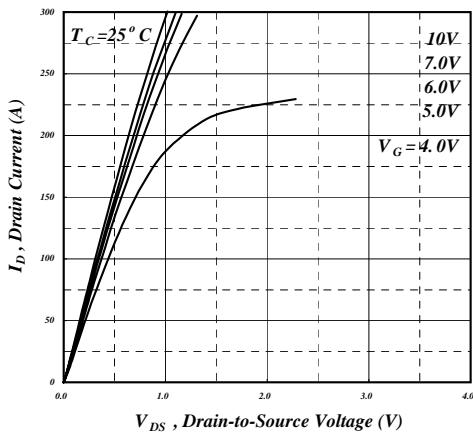


Fig 1. Typical Output Characteristics

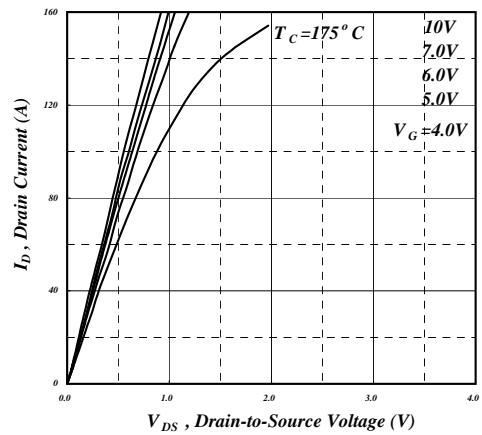


Fig 2. Typical Output Characteristics

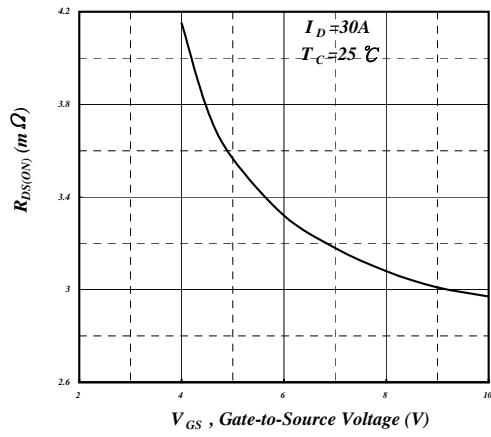


Fig 3. On-Resistance v.s. Gate Voltage

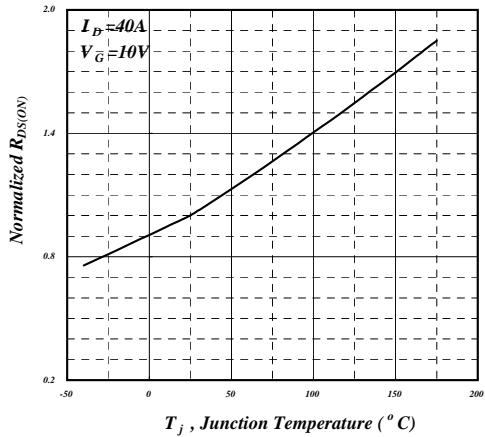


Fig 4. Normalized On-Resistance v.s. Junction Temperature

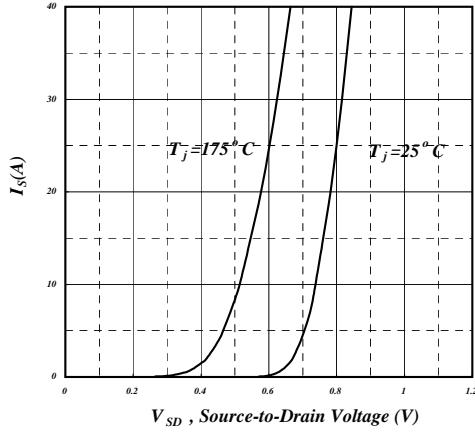


Fig 5. Forward Characteristic of Reverse Diode

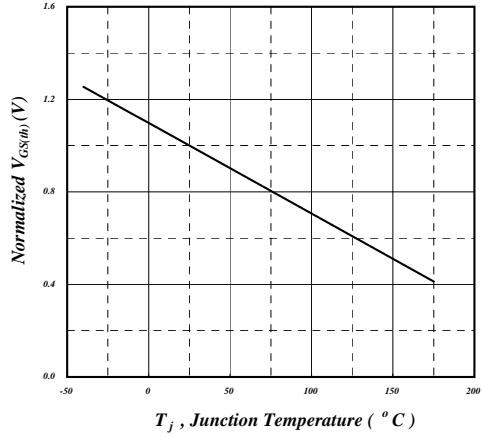


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

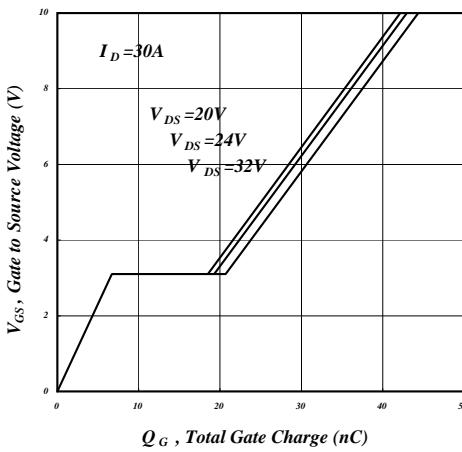


Fig 7. Gate Charge Characteristics

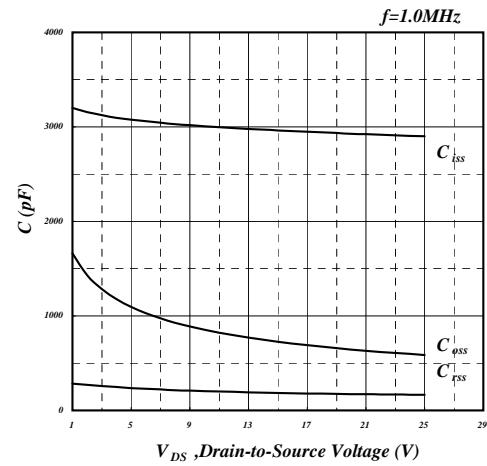


Fig 8. Typical Capacitance Characteristics

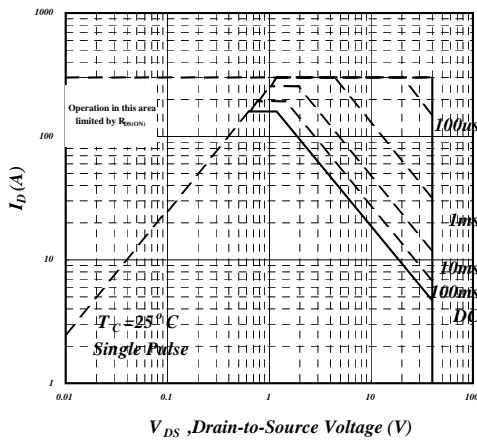


Fig 9. Maximum Safe Operating Area

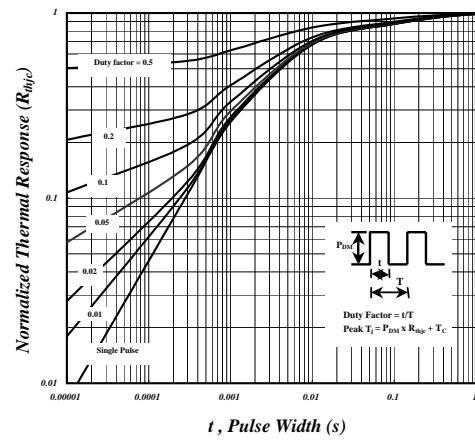


Fig 10. Effective Transient Thermal Impedance

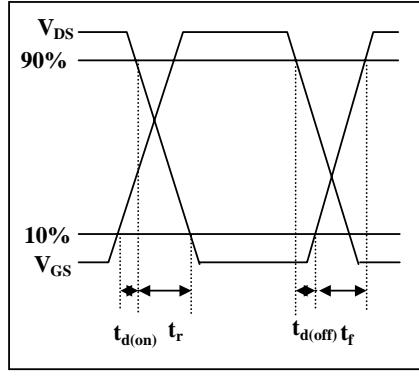


Fig 11. Switching Time Waveform

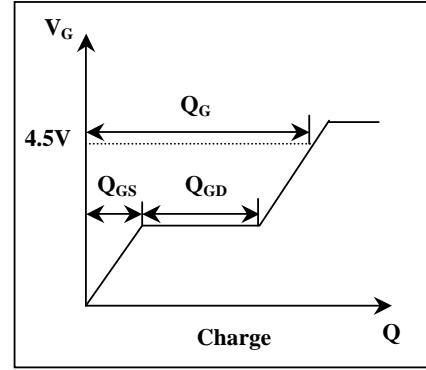


Fig 12. Gate Charge Waveform